

Final Call for Papers Issued for 14th International Conference on Microscopy of Semiconducting Materials

The 14th International Conference on Microscopy of Semiconducting Materials (MSMXIV) will be held at Oxford University, United Kingdom, April 11–14, 2005. It will focus on the latest developments in the study of the structural and electrical properties of semiconductors by the application of transmission and scanning electron microscopy (TEM, SEM), scanning probe microscopy (SPM), and x-ray-based methods.

Conference sessions will concentrate on key topics including state-of-the-art studies in high-resolution imaging and analytical electron microscopy, advanced SPM and SEM applications, novel epitaxial layer phenomena, the properties of quantum nanostructures, III–nitride developments, GeSi/Si for advanced

devices, metal–semiconductor contacts and silicides, and important effects of critical device processing treatments.

Invited speakers include P.E. Batson (IBM, Yorktown Heights), “Atomic-Resolution STEM”; B. Daudin (CEA, Grenoble) “GaN Quantum Dots”; D. Donnet (Philips, Eindhoven), “FIB for Device Failure Analysis”; R. Dunin-Borkowski (Cambridge University, U.K.), “Electron Holography of Semiconductors”; C. Hetherington (Oxford University, U.K.), “Aberration-Corrected HREM/STEM”; H.-L. Hwang (National Tsing Hua University, Hsinchu), “Nanoelectronics Developments in Taiwan”; P.M. Koenraad (Eindhoven University), “Cross-Sectional SPM of Nanostructures”; S. Mahajan (Arizona State University, Tempe), “Threading

Dislocations in GaN”; L. Samuelson (Lund University, Sweden), “Growth of Nanowires”; É. Spiecker (Kiel University, Germany), “Large-Area Analysis of Misfit Dislocations”; and P. Sutter (Brookhaven National Laboratory, New York), “High-Resolution Study of SiGe/Si Growth.”

The abstract deadline is December 3, 2004. Proceedings of the conference will be published.

The conference chairs are Tony Cullis (Sheffield University) and John Hutchison (Oxford University). The conference is endorsed by the Materials Research Society. For further details and information on abstract submission and registration, access the conference Web site at www.mrs.org.uk/MSMXIV or e-mail to lucy@mrs.org.uk. □